

Notice of References Cited	Application/Control No. 10/708,838	Applicant(s)/Patent Under Reexamination BEENAU ET AL.	
	Examiner Daniel I. Walsh	Art Unit 2876	Page 1 of 1

U.S. PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0131237	07-2004	Machida, Akihiro	382/124
*	B	US-2004/0155101	08-2004	Royer et al.	235/379
*	C	US-2005/0098621	05-2005	de Sylva, Robert Francis	235/379
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS		
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.